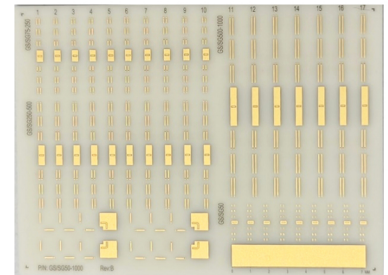


Calibration Substrate

GS/SG50-100 calibration substrate is designed to provide accurate probe tip calibration of RF probe family with GS/SG probe tips configuration and accommodates 50 to 1000 μm probe pitch variation.



Substrate Characteristics

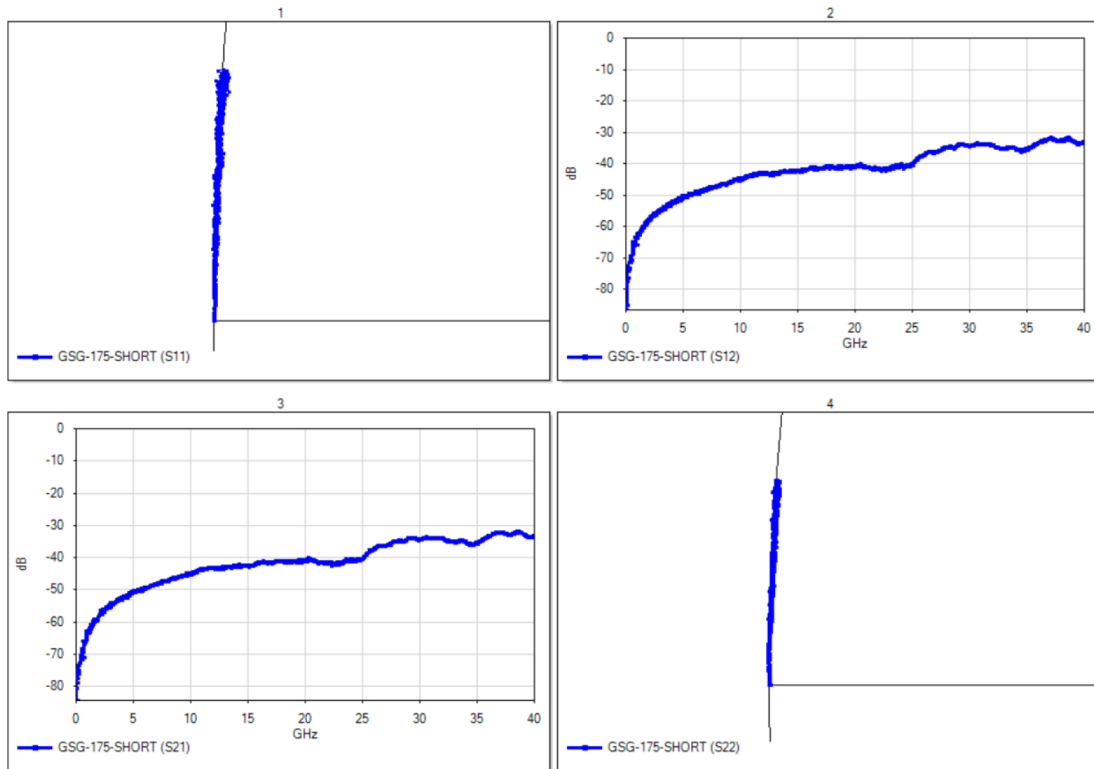
Material	Alumina
Size	15 x20 mm
Thickness	635 μm
Design or standards	Coplanar
Probe configuration	GS/SG
Supported probe pitch	50 to 1000 μm
Number of lumped standard groups	10 groups (GS/SG75-250) 7 groups (GS/SG500-1000) 10 groups (GS/SG250-500) 9 groups (GS/SG50)
Supported calibration methods	SOLT, LRM, SOLR
Typical resistance of the load	50 Ω
Typical load trimming accuracy error	+0.3%
Open standard Au pads on substrate	Au pads on substrate
Recommended overtravel for probes	10-20 μm

Electrical Characteristics

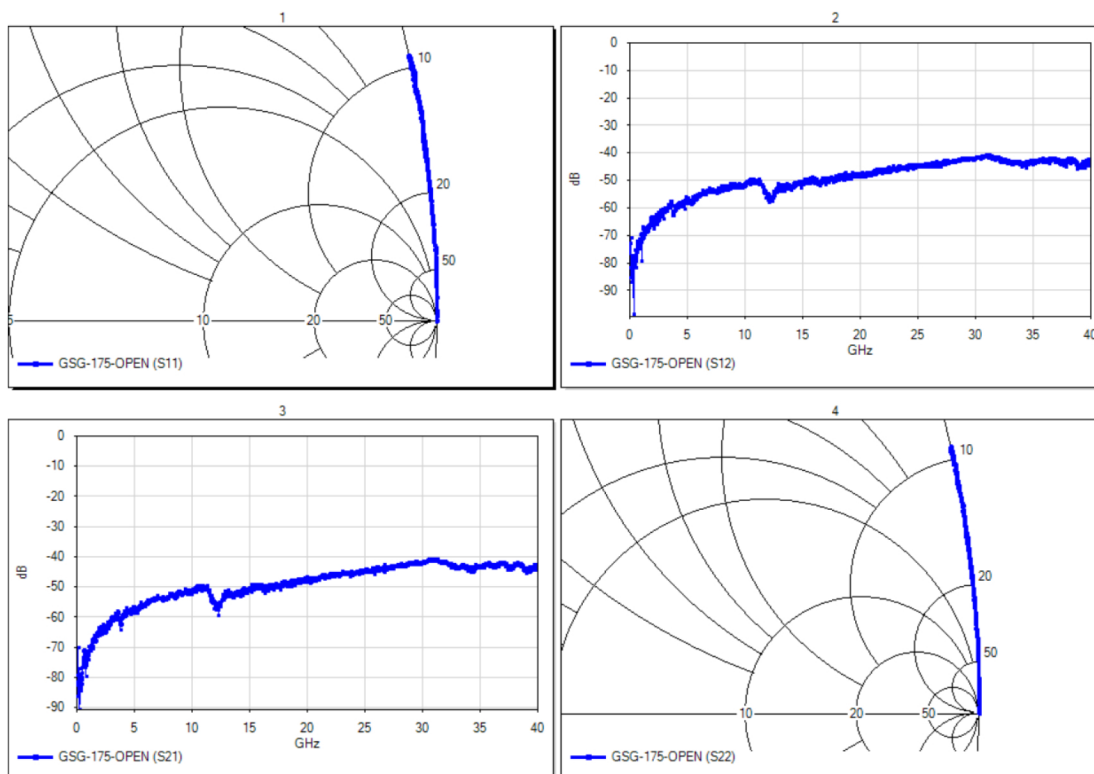
Nominal characteristic impedance	50 Ω
Dielectric Constant	9.9
Working Frequency	DC-67GHz
Electrical length of line, ps	
Thru	0.8 ps

Calibration Accuracy

The following screenshot shows RF probe contact calibration substrate short.



The following screenshot shows RF probe contact calibration substrate open.



Substrate layout

The calibration substrate includes various calibration structures such as parallel and 90-degree ones, which can meet the requirements of multiple ports.

